

MOSFETs Silicon P-/N-Channel MOS

# SSM6L807R

#### 1. Applications

· Power Management Switches

#### 2. Features

(1) Low drain-source on-resistance

#### Q1 N-channel:

 $R_{\mathrm{DS(ON)}} = 39.1~\mathrm{m}\Omega~(\mathrm{max})~(@V_{\mathrm{GS}} = 4.5~\mathrm{V})$ 

 $R_{\mathrm{DS(ON)}} = 53~\mathrm{m}\Omega~(\mathrm{max})~(@V_{\mathrm{GS}} = 2.5~\mathrm{V})$ 

 $R_{DS(ON)} = 82 \text{ m}\Omega \text{ (max) } (@V_{GS} = 1.8 \text{ V})$ 

#### Q2 P-channel:

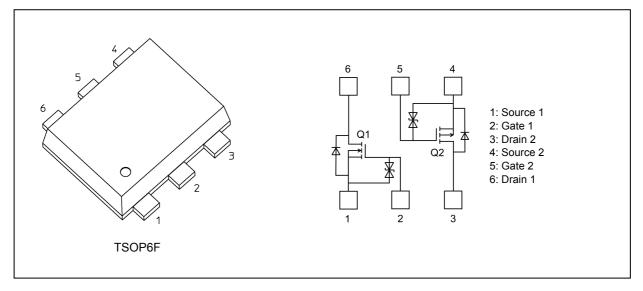
 $R_{\mathrm{DS(ON)}} = 45~\mathrm{m}\Omega~(\mathrm{max})~(@V_{\mathrm{GS}} = -10~\mathrm{V})$ 

 $R_{DS(ON)} = 56 \text{ m}\Omega \text{ (max) (@V_{GS} = -4.5 V)}$ 

 $R_{\rm DS(ON)}$  = 76 m $\Omega$  (max) (@V\_{\rm GS} = -2.5 V)

 $R_{DS(ON)} = 157 \text{ m}\Omega \text{ (max) } (@V_{GS} = -1.8 \text{ V})$ 

## 3. Packaging and Internal Circuit





#### 4. Absolute Maximum Ratings (Note)

#### 4.1. Q1 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	30	V
Gate-source voltage	(Note 3)	V <sub>GSS</sub>	±12	V
Drain current (DC)	(Note 1)	I <sub>D</sub>	4	Α
Drain current (pulsed)	(Note 1), (Note 2)	I <sub>DP</sub>	10	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW)  $\leq$  10 ms, duty  $\leq$  1 %

Note 3: Reverse bias between gate and source is guaranteed with pulse rating.

### 4.2. Q2 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	-20	V
Gate-source voltage	(Note 3)	$V_{GSS}$	±12	V
Drain current (DC)	(Note 1)	I <sub>D</sub>	-4	Α
Drain current (pulsed)	(Note 1), (Note 2)	I <sub>DP</sub>	-10	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW)  $\leq$  10 ms, duty  $\leq$  1 %

Note 3: Reverse bias between gate and source is guaranteed with pulse rating.

# 4.3. Absolute Maximum Ratings (Unless otherwise specified, T<sub>a</sub> = 25 °C) (Q1, Q2 Common)

Chara	cteristics		Symbol	Rating	Unit
Power dissipation		(Note 1)	P <sub>D</sub>	1.4	W
Power dissipation	t ≤ 10 s	(Note 1)		1.8	]
Channel temperature			T <sub>ch</sub>	150	°C
Storage temperature			T <sub>stg</sub>	-55 to 150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Device mounted on an FR4 board.(total rating) (25.4 mm  $\times$  25.4 mm  $\times$  1.6 mm, Cu pad: 645 mm<sup>2</sup>)

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance, R<sub>th(ch-a)</sub>, and the drain power dissipation, P<sub>D</sub>, vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.



#### 5. Electrical Characteristics

## 5.1. Q1 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 10 \text{ V}$	_	_	±10	μΑ
Drain cut-off current		I <sub>DSS</sub>	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V	_	_	1	μА
Drain-source breakdown voltage		V <sub>(BR)DSS</sub>	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	30	_	_	V
Drain-source breakdown voltage	(Note 1)	V <sub>(BR)DSX</sub>	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = -12 V	18	_	_	V
Gate threshold voltage	(Note 2)	$V_{th}$	V <sub>DS</sub> = 3 V, I <sub>D</sub> = 1 mA	0.4	_	1.0	V
Drain-source on-resistance	(Note 3)	R <sub>DS(ON)</sub>	I <sub>D</sub> = 2.0 A, V <sub>GS</sub> = 4.5 V	_	30	39.1	mΩ
			I <sub>D</sub> = 1.0 A, V <sub>GS</sub> = 2.5 V	_	37	53	
			I <sub>D</sub> = 0.5 A, V <sub>GS</sub> = 1.8 V	_	46	82	

Note 1: If a reverse bias is applied between gate and source, this device enters  $V_{(BR)DSX}$  mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (1 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .

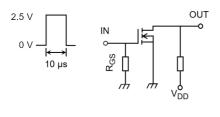
Take this into consideration when using the device.

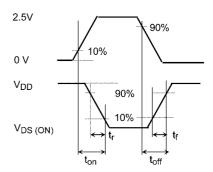
Note 3: Pulse measurement.

### 5.2. Q1 Dynamic Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 15 V , V <sub>GS</sub> = 0 V,	_	310	_	pF
Reverse transfer capacitance	C <sub>rss</sub>	f = 1 MHz	_	20	_	
Output capacitance	C <sub>oss</sub>		_	52	_	
Switching time (turn-on time)	t <sub>on</sub>	$V_{DD}$ = 15 V, $I_{D}$ = 1.0 A, $V_{GS}$ = 0 to 2.5 V, $R_{GS}$ = 4.7 $\Omega$		26	_	ns
Switching time (turn-off time)	t <sub>off</sub>	Duty $\leq$ 1 %, Input: $t_r$ , $t_f$ < 5 ns Common source, See Chapter 5.3	_	17	_	

#### 5.3. Q1 Switching Time Test Circuit





**Switching Time Test Circuit** 

Input Waveform/Output Waveform

### 5.4. Q1 Gate Charge Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	$Q_g$	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 4.0 A,	_	3.2	_	nC
Gate-source charge 1	Q <sub>gs1</sub>	$V_{GS} = 4.5 V$	_	0.5	_	
Gate-drain charge	Q <sub>gd</sub>		_	0.7	_	



## 5.5. Q1 Source-Drain Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage (Note	l) V <sub>DSF</sub>	I <sub>DR</sub> = 4.0 A, V <sub>GS</sub> = 0 V	_	0.8	1.2	V

Note 1: Pulse measurement.

## 5.6. Q2 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 10 \text{ V}$	_	_	±1	μА
Drain cut-off current		I <sub>DSS</sub>	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0 V	_	_	-1	μА
Drain-source breakdown voltage		V <sub>(BR)DSS</sub>	I <sub>D</sub> = -1 mA, V <sub>GS</sub> = 0 V	-20	_	_	V
Drain-source breakdown voltage	(Note 1)	V <sub>(BR)DSX</sub>	I <sub>D</sub> = -1 mA, V <sub>GS</sub> = 8 V	-12	_	_	V
Gate threshold voltage	(Note 2)	$V_{th}$	$V_{DS} = -3 \text{ V}, I_{D} = -1 \text{ mA}$	-0.5	_	-1.2	V
Drain-source on-resistance	(Note 3)	R <sub>DS(ON)</sub>	I <sub>D</sub> = -3.5 A, V <sub>GS</sub> = -10 V	_	36	45	mΩ
			I <sub>D</sub> = -3.0 A, V <sub>GS</sub> = -4.5 V	_	44	56	
			I <sub>D</sub> = -2.0 A, V <sub>GS</sub> = -2.5 V	_	60	76	
			I <sub>D</sub> = -0.5 A, V <sub>GS</sub> = -1.8 V	_	83	157	

Note 1: If a reverse bias is applied between gate and source, this device enters  $V_{(BR)DSX}$  mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (-1 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .

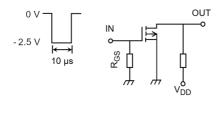
Take this into consideration when using the device.

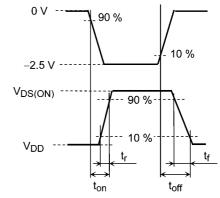
Note 3: Pulse measurement.

## 5.7. Q2 Dynamic Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -10 V , V <sub>GS</sub> = 0 V,	_	480	_	pF
Reverse transfer capacitance	C <sub>rss</sub>	f = 1 MHz	_	76		
Output capacitance	C <sub>oss</sub>		_	90		
Switching time (turn-on time)	t <sub>on</sub>	$V_{DD}$ = -10 V, $I_{D}$ = -0.5 A, $V_{GS}$ = 0 to -2.5 V, $R_{GS}$ = 4.7 $\Omega$	_	21	_	ns
Switching time (turn-off time)	t <sub>off</sub>	Duty $\leq$ 1 %, V <sub>IN</sub> : $t_r$ , $t_f$ < 5 ns, Common source, See Chapter 5.8	_	54		

#### 5.8. Q2 Switching Time Test Circuit





**Switching Time Test Circuit** 

Input Waveform/Output Waveform



## 5.9. Q2 Gate Charge Characteristics (Unless otherwise specified, Ta = 25 °C)

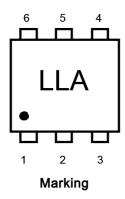
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)		$V_{DD}$ = -10 V, $I_D$ = -4.0 A,	_	6.74	_	nC
Gate-source charge 1	Q <sub>gs1</sub>	V <sub>GS</sub> = -4.5 V	_	0.95	_	
Gate-drain charge	Q <sub>gd</sub>		_	1.50	_	

## 5.10. Q2 Source-Drain Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage	(Note 1)	$V_{DSF}$	I <sub>DR</sub> = 4.0 A, V <sub>GS</sub> = 0 V	_	0.87	1.2	V

Note 1: Pulse measurement.

## 6. Marking





#### 7. Characteristics Curves (Note)

### 7.1. Q1 Characteristics Curves

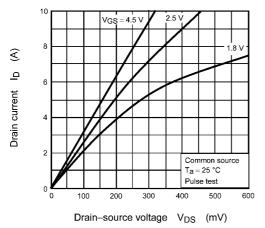


Fig. 7.1.1 I<sub>D</sub> - V<sub>DS</sub>

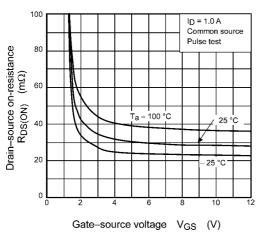


Fig. 7.1.3 R<sub>DS(ON)</sub> - V<sub>GS</sub>

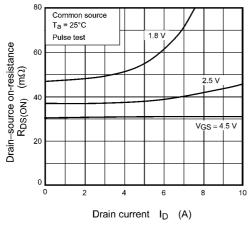


Fig. 7.1.5 R<sub>DS(ON)</sub> - I<sub>D</sub>

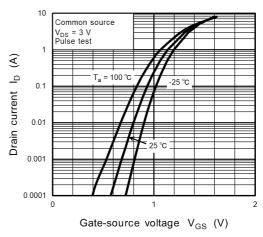


Fig. 7.1.2 I<sub>D</sub> - V<sub>GS</sub>

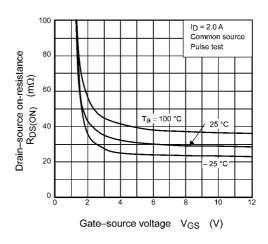


Fig. 7.1.4 R<sub>DS(ON)</sub> - V<sub>GS</sub>

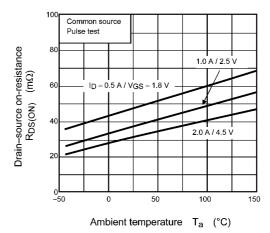
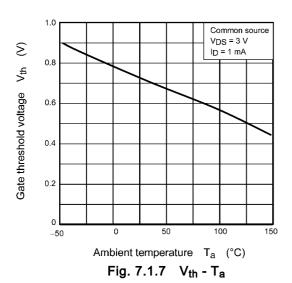
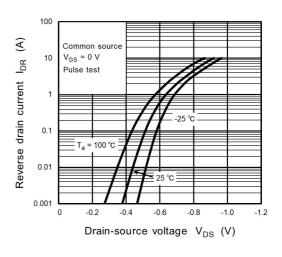
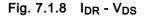


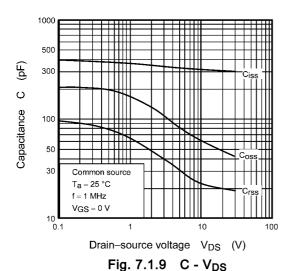
Fig. 7.1.6 R<sub>DS(ON)</sub> - T<sub>a</sub>











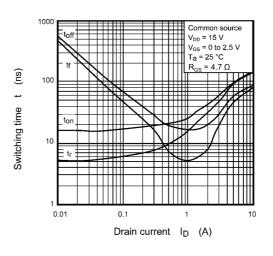
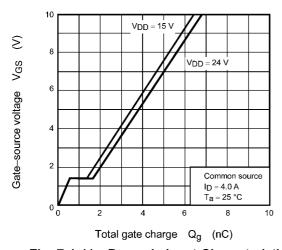


Fig. 7.1.10 t - I<sub>D</sub>



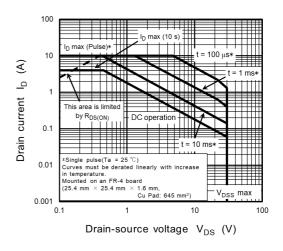


Fig. 7.1.11 Dynamic Input Characteristics

Fig. 7.1.12 Safe Operating Area

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#### 7.2. Q2 Characteristics Curves

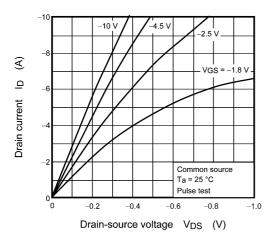
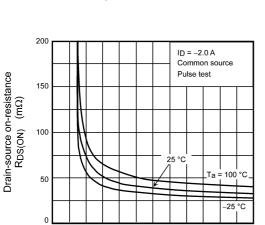


Fig. 7.2.1 I<sub>D</sub> - V<sub>DS</sub>



Gate-source voltage V<sub>GS</sub> (V) Fig. 7.2.3 R<sub>DS(ON)</sub> - V<sub>GS</sub>

-10

-12

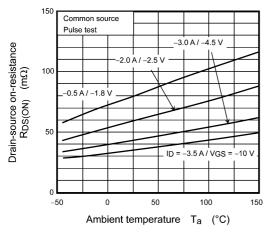


Fig. 7.2.5 R<sub>DS(ON)</sub> - T<sub>a</sub>

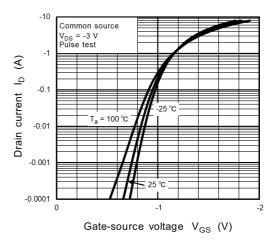


Fig. 7.2.2 I<sub>D</sub> - V<sub>GS</sub>

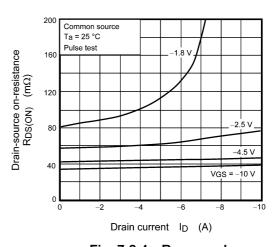


Fig. 7.2.4 R<sub>DS(ON)</sub> - I<sub>D</sub>

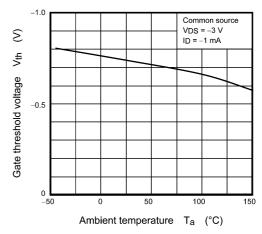


Fig. 7.2.6 V<sub>th</sub> - T<sub>a</sub>



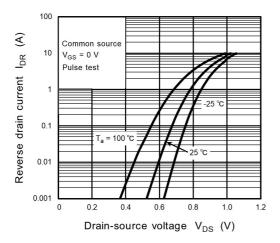


Fig. 7.2.7 IDR - VDS

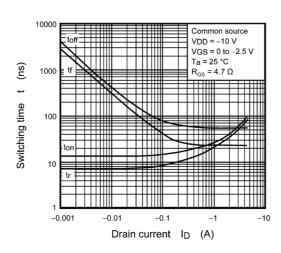


Fig. 7.2.9 t - I<sub>D</sub>

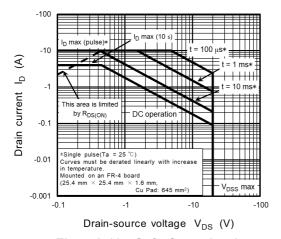


Fig. 7.2.11 Safe Operating Area

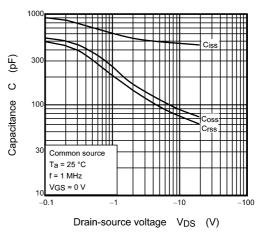


Fig. 7.2.8  $\,$  C -  $\,$  V<sub>DS</sub>

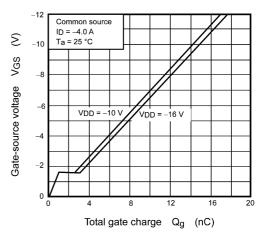
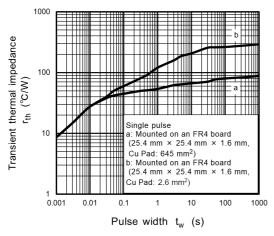


Fig. 7.2.10 Dynamic Input Characteristics

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## 7.3. Characteristics Curves (Q1, Q2 Common)



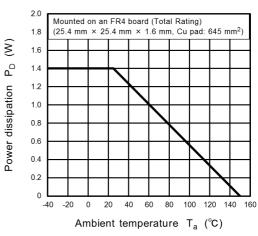


Fig. 7.3.1 r<sub>th</sub> - t<sub>w</sub>

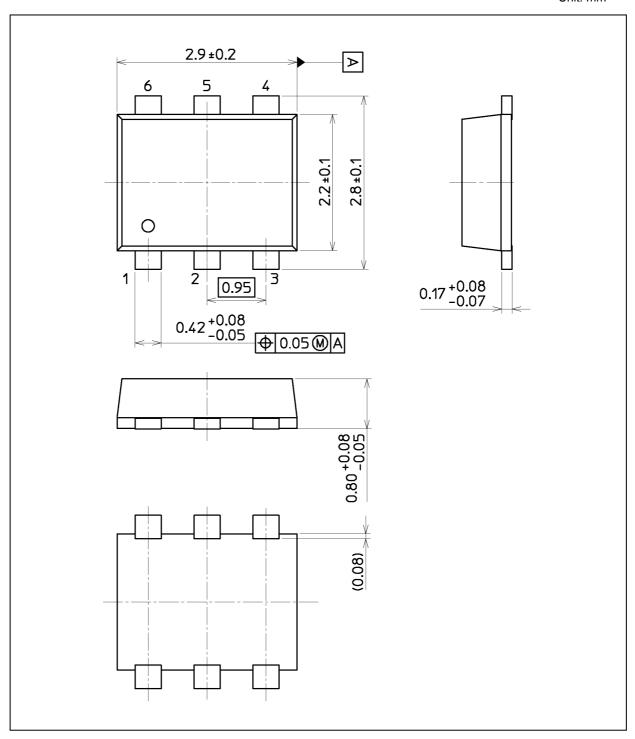
Fig. 7.3.2 P<sub>D</sub> - T<sub>a</sub>

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



## **Package Dimensions**

Unit: mm



Weight: 0.016 g (typ.)

	Package Name(s)
Nickname: TSOP6F	

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